

## N-Channel Enhancement Mode Power MOSFET

**Description**

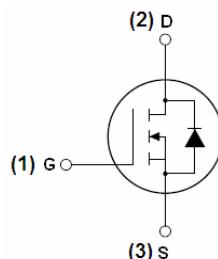
The SL30N06D uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

**General Features**

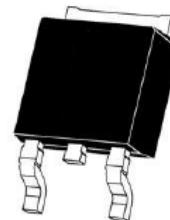
- $V_{DS} = 60V, I_D = 30A$
- $R_{DS(ON)} < 35m\Omega @ V_{GS}=10V$
- High density cell design for ultra low  $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

**Application**

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



TO-252-2L top view

**Absolute Maximum Ratings ( $T_c=25^\circ C$  unless otherwise noted)**

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	30	A
Drain Current-Continuous( $T_c=100^\circ C$ )	$I_D (100^\circ C)$	14	A
Pulsed Drain Current	$I_{DM}$	60	A
Maximum Power Dissipation	$P_D$	45	W
Derating factor		0.3	W/ $^\circ C$
Single pulse avalanche energy (Note 5)	$E_{AS}$	72	mJ
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	$^\circ C$

**Thermal Characteristic**

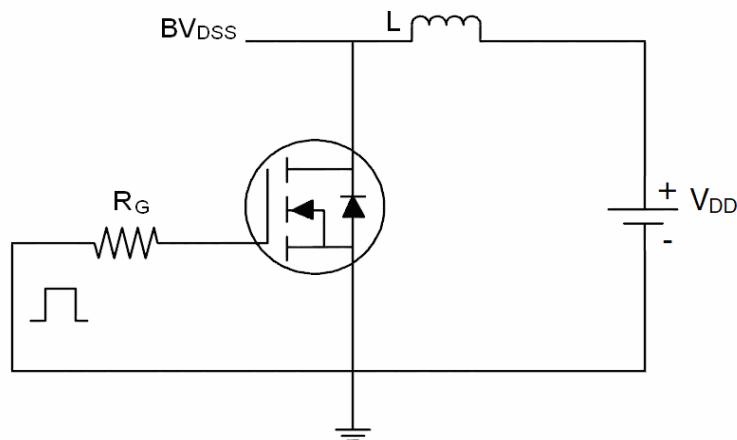
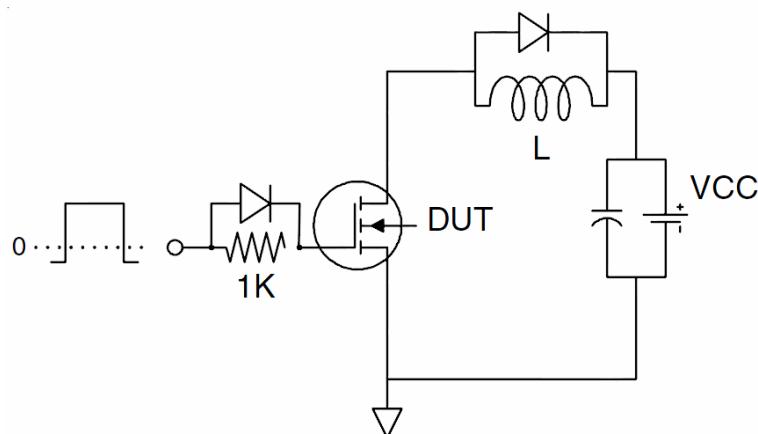
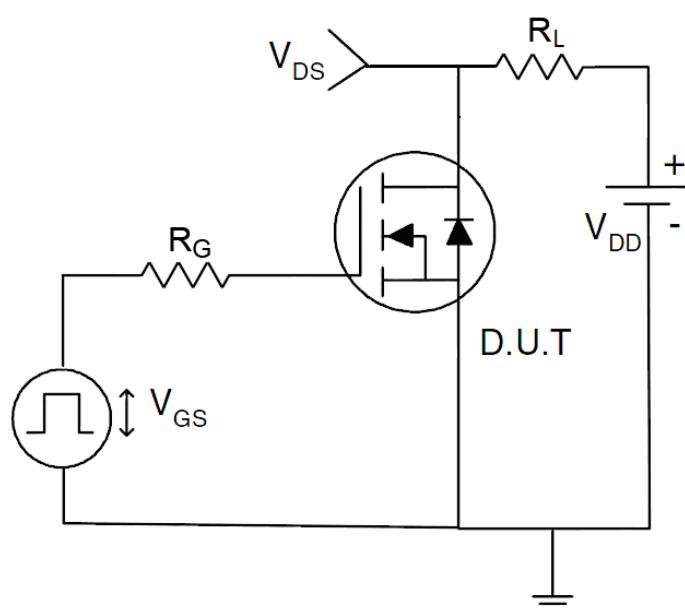
Thermal Resistance,Junction-to-Case <sup>(Note 2)</sup>	$R_{\theta JC}$	3.3	°C/W
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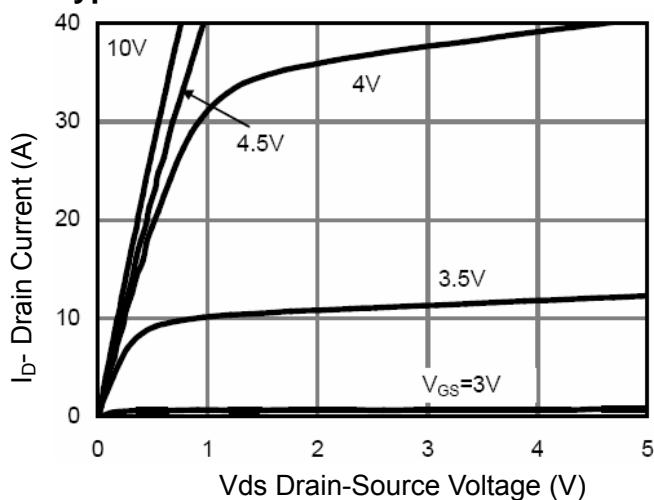
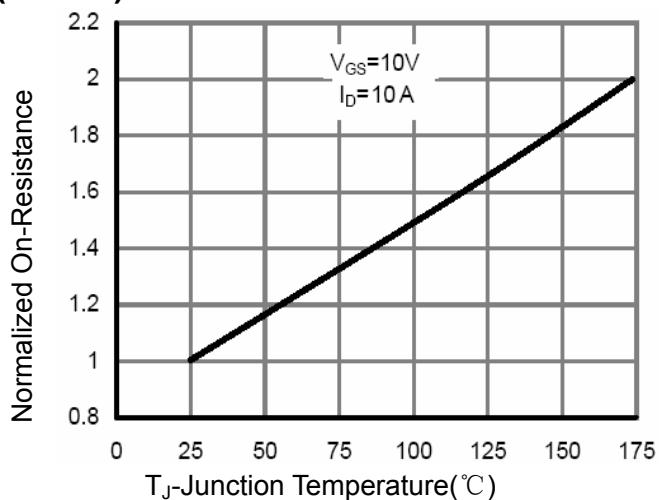
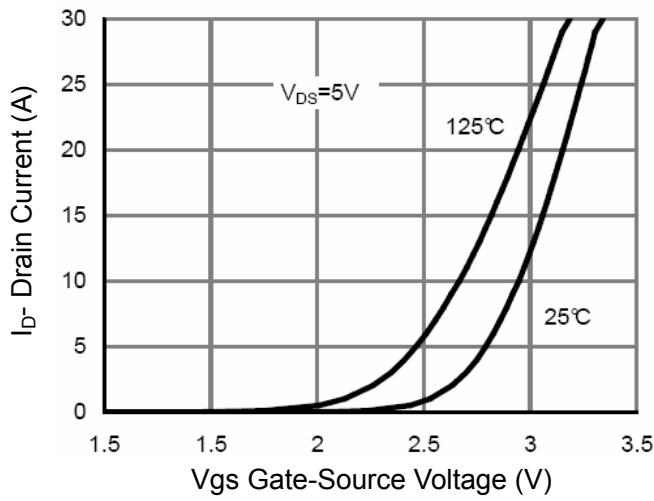
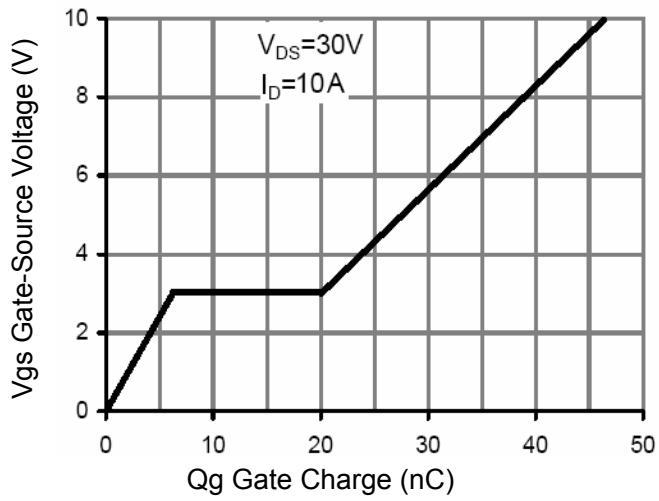
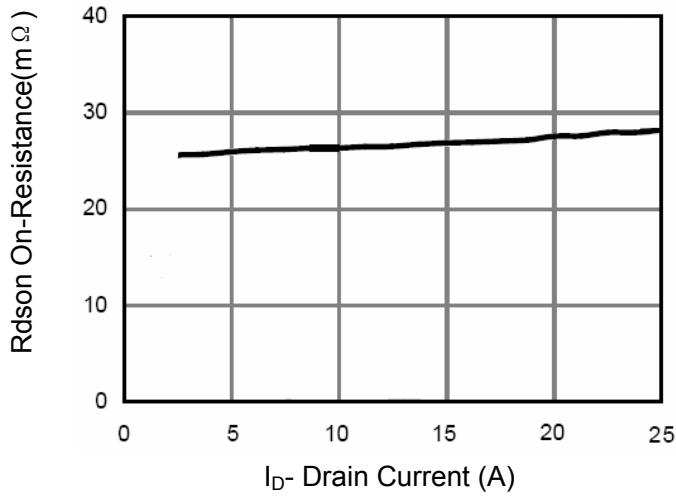
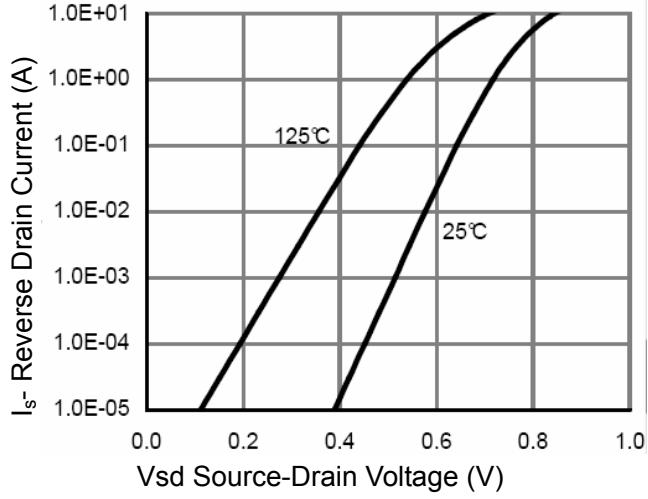
**Electrical Characteristics ( $T_c=25^\circ C$  unless otherwise noted)**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$V_{DSS}$	$V_{GS}=0V, I_D=250\mu A$	60	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=60V, V_{GS}=0V$	-	-	1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
<b>On Characteristics</b> <sup>(Note 3)</sup>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.2	1.6	2.5	V
Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=30A$	-	27	35	$m\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS}=5V, I_D=5A$	11	-	-	S
<b>Dynamic Characteristics</b> <sup>(Note 4)</sup>						
Input Capacitance	$C_{iss}$	$V_{DS}=30V, V_{GS}=0V,$ $F=1.0MHz$	-	500	-	PF
Output Capacitance	$C_{oss}$		-	60	-	PF
Reverse Transfer Capacitance	$C_{rss}$		-	25	-	PF
<b>Switching Characteristics</b> <sup>(Note 4)</sup>						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=30V, I_D=2A, R_L=6.7\Omega$ $V_{GS}=10V, R_G=3\Omega$	-	5	-	nS
Turn-on Rise Time	$t_r$		-	2.6	-	nS
Turn-Off Delay Time	$t_{d(off)}$		-	16.1	-	nS
Turn-Off Fall Time	$t_f$		-	2.3	-	nS
Total Gate Charge	$Q_g$	$V_{DS}=30V, I_D=4.5A,$ $V_{GS}=10V$	-	47	-	nC
Gate-Source Charge	$Q_{gs}$		-	6	-	nC
Gate-Drain Charge	$Q_{gd}$		-	14	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage <sup>(Note 3)</sup>	$V_{SD}$	$V_{GS}=0V, I_S=30A$	-		1.2	V
Diode Forward Current <sup>(Note 2)</sup>	$I_S$		-	-	20	A
Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ C, IF = 30A$ $di/dt = 100A/\mu s$ <sup>(Note 3)</sup>	-	35	-	nS
Reverse Recovery Charge	$Q_{rr}$		-	53	-	nC
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production
5. EAS condition:  $T_j=25^\circ C, V_{DD}=30V, V_{G}=10V, L=0.5mH, R_g=25\Omega$

**Test Circuit****1) E<sub>AS</sub> test Circuit****2) Gate charge test Circuit****3) Switch Time Test Circuit**

**Typical Electrical and Thermal Characteristics (Curves)****Figure 1 Output Characteristics****Figure 4 Rdson-Junction Temperature****Figure 2 Transfer Characteristics****Figure 5 Gate Charge****Figure 3 Rdson- Drain Current****Figure 6 Source- Drain Diode Forward**

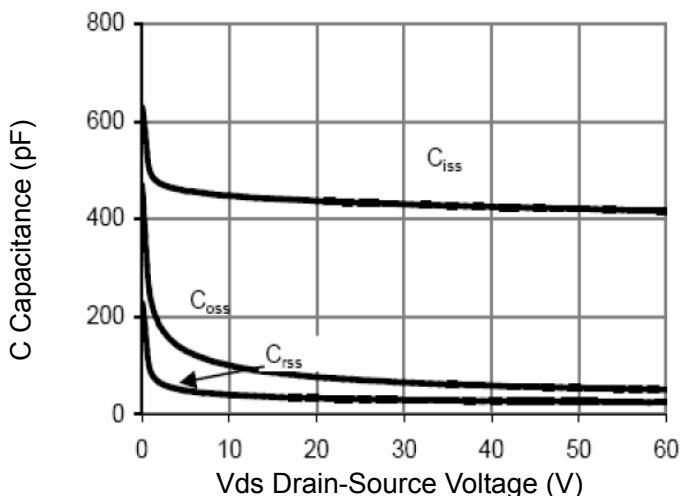


Figure 7 Capacitance vs Vds

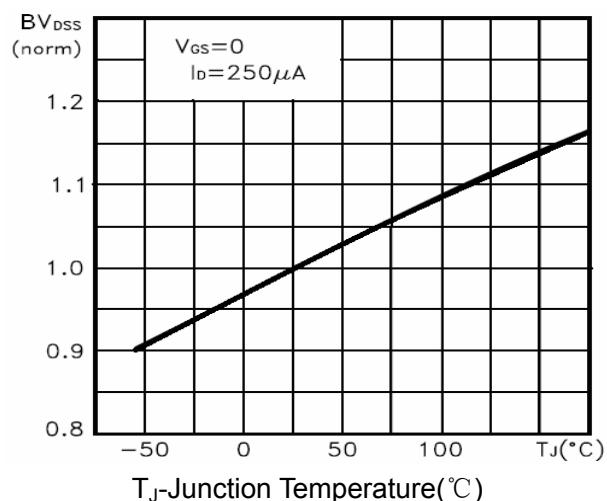
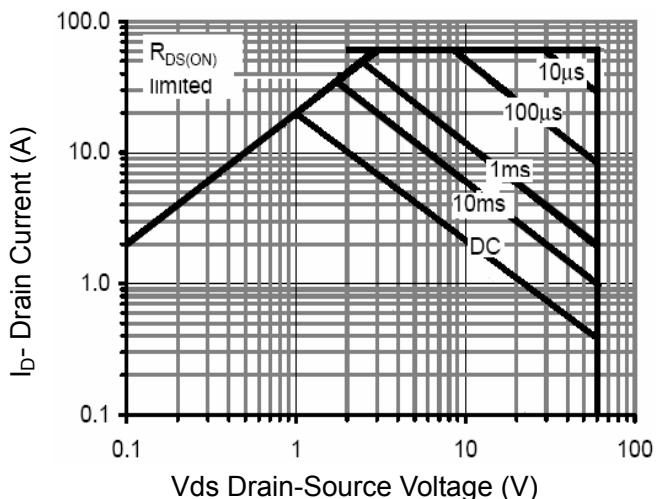
Figure 9  $BV_{DSS}$  vs Junction Temperature

Figure 8 Safe Operation Area

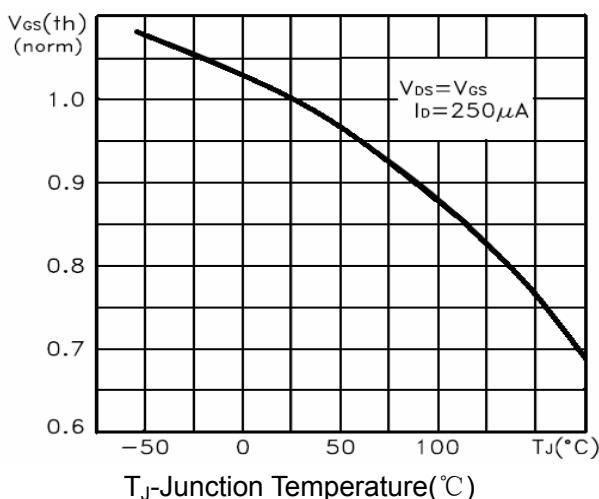
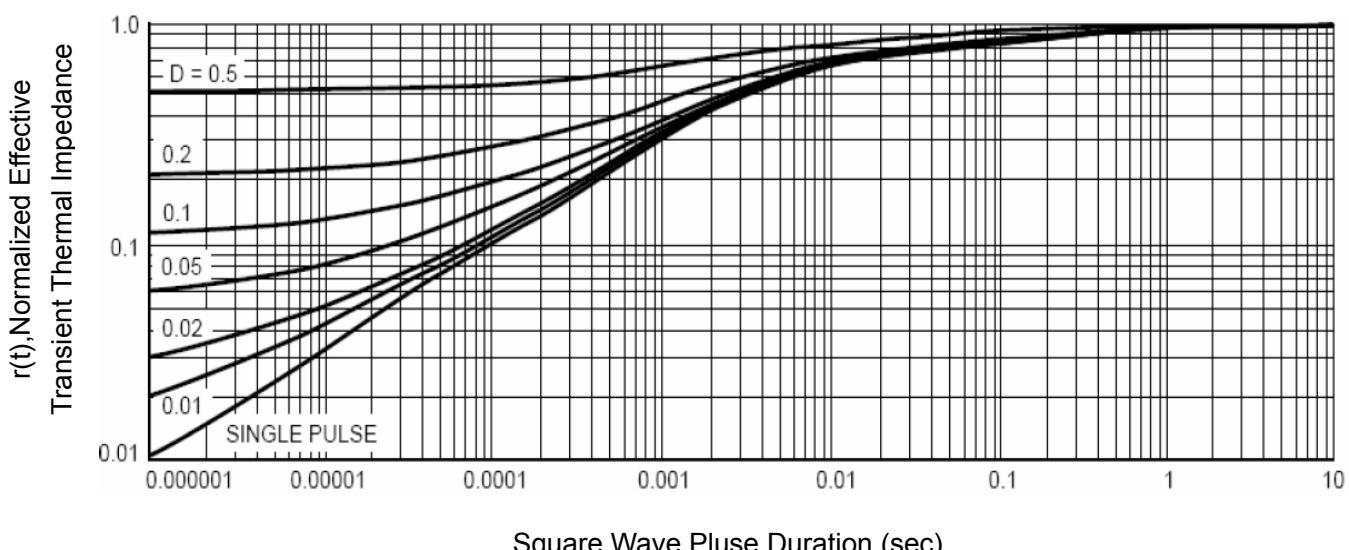
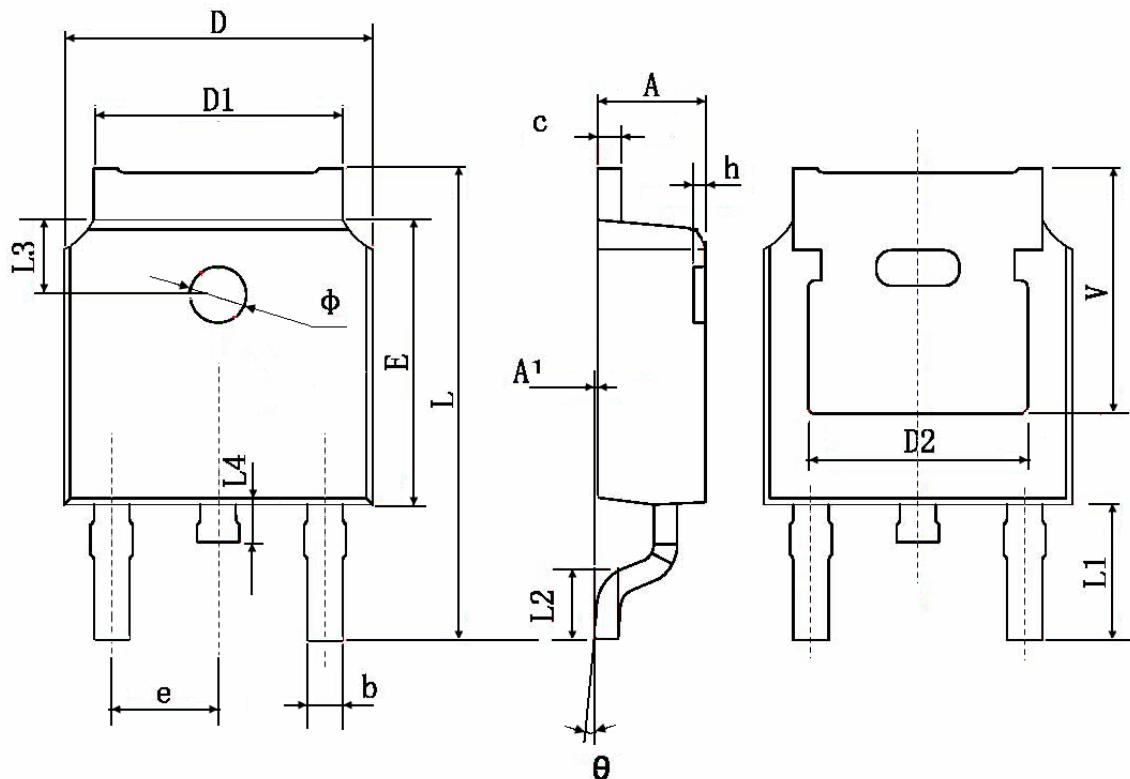
Figure 10  $V_{GS(\text{th})}$  vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance

## TO-252 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A <sup>1</sup>	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D <sup>1</sup>	5.100	5.460	0.201	0.215
D <sup>2</sup>	0.483 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L <sup>1</sup>	2.900 TYP.		0.114 TYP.	
L <sup>2</sup>	1.400	1.700	0.055	0.067
L <sup>3</sup>	1.600 TYP.		0.063 TYP.	
L <sup>4</sup>	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	